Application/Control No. Applicant(s)/Patent Under Reexamination 10/767,364 YEH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 1713 Mei Q. Huang **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY * US-6,309,707 10-2001 Mayer et al. 427/386 Α * 524/544 07-1991 US-5,032,641 Nanishi et al. В US-С US-D US-Ε F US-US-G н US-US-US-J US-Κ US-L US М FOREIGN PATENT DOCUMENTS

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